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LM9810/20 10/12-Bit Image Sensor Processor Analog Front End

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Absolute Maximum Ratings (Notes 1 & 2)

Positive Supply Voltage (V+=VA=VD)	
With Respect to GND=AGND=DGND	6.5V
Voltage On Any Input or Output Pin	-0.3V to V++0.3V
Input Current at any pin (Note 3)	±25mA
Package Input Current (Note 3)	±50mA
Package Dissipation at $T_A = 25^{\circ}C$	(Note 4)
ESD Susceptibility (Note 5)	
Human Body Model	2000V
Soldering Information	
Infrared, 10 seconds (Note 6)	300°C
Storage Temperature	-65°C to +150°C

Operating Ratings (Notes 1 & 2)

Electrical Characteristics

The following specifications apply for AGND=DGND=0V, VA=VD=+5.0V_{DC}, f_{MCLK} =24MHz, R_s =25 Ω . Boldface limits apply for $T_A=T_J=T_{MIN}$ to T_{MAX} ; all other limits T_A = T_J =25°C. (Notes 7, 8, & 12)

Symbol	Parameter	Conditions	Typical (Note 9)	Limits (Note 10)	Units (Limits)
CCD/CIS S	ource Requirements for Full Specified A	Accuracy and Dynamic Range (Note	12)		
V _{OS PEAK}	Sensor's Maximum Peak Differential Signal Range	Gain = 0.933 Gain = 3.0 Gain = 9.0	2.1 0.65 0.21		V V V
Analog Inp	but Characteristics			•	
	OS _R , OS _G , OS _B Input Capacitance		5		pF
		Measured with $OS = 3.5V_{DC}$ CDS disabled, selected OS input	20	25	μA (max)
	OS_R , OS_G , OS_B Input Leakage Current	CDS disabled, unselected OS input	10		nA
Coarse Co	Ior Balance PGA Characteristics			•	
	Monotonicity			5	bits (min)
	G ₀ (Minimum PGA Gain)	PGA Setting = 0	0.93	.90 .96	V/V (min) V/V (max)
	G ₃₁ (Maximum PGA Gain)	PGA Setting = 31	3.0	2.96 3.15	V/V (min) V/V (max)
	x3 Boost Gain	x3 Boost Setting On (bit B5 of Gain Register is set)	3.0	2.93 3.05	V/V (min) V/V (max)
	Gain Error at any gain (Note 13)		±0.4	1.67	% (max)
Internal Re	eference Characteristics				
V _{REFMID}	Mid Supply Output Voltage		2.5		V
V _{REF+}	Positive Reference Output Voltage		3.5		V
V _{REF-}	Negative Reference Output Voltage		1.5		V
ΔV_{REF}	Differential Reference Voltage V _{REF+} - V _{REF-}		2.0		V

	to T_{MAX} ; all other limits $T_A = T_J = 25^{\circ}$ C. All LSI				
Symbol	Parameter	Conditions	Typical (Note 9)	Limits (Note 10)	Units (Limits)
ADC Chara	acteristics				
	Resolution with No Missing Codes			10	bits (min
INL	Integral Non-Linearity Error (Note 11)		±0.35	±1.5	LSB (max
DNL	Differential Non-Linearity		±0.25	±1.0	LSB (max
Full Chanr	nel Linearity (Note 14)		•	•	
INL	Integral Non-Linearity Error (Note 11)		±0.9		LSB
DNL	Differential Non-Linearity		±0.40		LSB
Static Offs	set DAC Characteristics				
	Monotonicity			6	bits (min
	Offset DAC LSB size	PGA gain = 1	5	3.4 6.4	LSB (mir LSB (ma
	Offset DAC Adjustment Range	PGA gain = 1	±150	±140	LSB (mir
System Ch	naracteristics (see section 1.7.1, Internal	Offsets)			
С	Analog Channel Gain Constant (ADC Codes/V)	Includes voltage reference variation, gain setting = 1	502	468 532	LSB (mir LSB (ma
V _{OS1}	Pre-Boost Analog Channel Offset Error, CCD Mode		4.4	-7.2 +15.7	LSB (mir LSB (ma
V _{OS1}	Pre-Boost Analog Channel Offset Error, CIS Mode		4.5	-6.5 +15.2	LSB (mir LSB (ma
V _{OS2}	Pre-PGA Analog Channel Offset Error		-10	-28 +5.3	LSB (mir LSB (ma
V _{OS3}	Post-PGA Analog Channel Offset Error		-11	-30.6 +7.3	LSB (mir LSB (ma
The followir	0 Electrical Characteristics ng specifications apply for AGND=DGND=0V, to T _{MAX} ; all other limits T _A =T _J =25°C. All LSI Parameter	VA=VD=+5.0V _{DC} , f _{MCLK} =24MHz, R	's 12 bit ADC. (N Typical	otes 7, 8, & 1	Units
100.01			(Note 9)	(Note 10)	(Limits
ADC Chara		1			
	Resolution with No Missing Codes			12	bits (mir
INL	Integral Non-Linearity Error (Note 11)		±1.1	±4.0	LSB (ma
DNL	Differential Non-Linearity		±0.6	+1.75 -1.0	LSB (ma
Full Chanr	nel Linearity (Note 14)				
	Integral Non-Linearity Error (Note 11)		±3.4		LSB
INL					

Symbol	Parameter	Conditions	Typical (Note 9)	Limits (Note 10)	Units (Limits)
Static Offs	et DAC Characteristics	ł	!	ļ	
	Monotonicity			6	bits (min)
	Offset DAC LSB size	PGA gain = 1	20	14 26	LSB (min) LSB (max
	Offset DAC Adjustment Range	PGA gain = 1	±590	±575	LSB (min)
System Ch	aracteristics (see section 1.7.1, Internal	Offsets)	•		
С	Analog Channel Gain Constant (ADC Codes/V)	Includes voltage reference variation, gain setting = 1	2008	1873 2129	LSB (min) LSB (max
V _{OS1}	Pre-Boost Analog Channel Offset Error, CCD Mode		17.6	-32.1 +68.9	LSB (min LSB (max
V _{OS1}	Pre-Boost Analog Channel Offset Error, CIS Mode		18	-22.2 +57	LSB (min LSB (max
V _{OS2}	Pre-PGA Analog Channel Offset Error		-40	-94.3 +16.4	LSB (min LSB (max
V _{OS3}	Post-PGA Analog Channel Offset Error		-44	-121 +28	LSB (min LSB (max
The followin	g specifications apply for AGND=DGND=OV, to T _{MAX} ; all other limits T _A =T _J =25°C. (Notes Parameter	VA=VD=+5.0V _{DC} , f _{MCLK} =24MHz, R _s	Typical	Limits	Units
			(Note 9)	(Note 10)	(Limits)
-	LK, NewLine, SampCLK Digital Input Cha	1			
V _{IN(1)}	Logical "1" Input Voltage	VD=5.25V		2.0	V (max)
V _{IN(0)}	Logical "0" Input Voltage	VD=4.75V		0.8	V (min)
I _{IN}	Input Leakage Current	V _{IN} =VD V _{IN} =DGND	0.1 -0.1		µA(max)

-			(Note 9)	(Note 10)	(Limits)
00-D2, MC	LK, NewLine, SampCLK Digital Input	Characteristics			
V _{IN(1)}	Logical "1" Input Voltage	VD=5.25V		2.0	V (max)
V _{IN(0)}	Logical "0" Input Voltage	VD=4.75V		0.8	V (min)
I _{IN}	Input Leakage Current	V _{IN} =VD V _{IN} =DGND	0.1 -0.1		μA(max) μA(max)
C _{IN}	Input Capacitance		5		pF
D0-D5 Digi	tal Output Characteristics				
V _{OUT(1)}	Logical "1" Output Voltage	VD=4.75V, I _{OUT} =-360µA VD=4.75V, I _{OUT} =-10µA		2.4 4.4	V (min) V (min)
V _{OUT(0)}	Logical "0" Output Voltage	VD=5.25V, I _{OUT} =1.6mA		0.4	V (max)
I _{OUT}	TRI-STATE [®] Output Current (D0-D5 only)	V _{OUT} =DGND V _{OUT} =VD	0.1 -0.1		μΑ μΑ
Power Sup	ply Characteristics				
I _A	Analog Supply Current	Operating Standby with input clocks stopped Standby with input clocks running	45 0.8 3.0	57 0.9	mA (max mA (max mA
Ι _D	Digital Supply Current (Note 15)	Operating Standby with input clocks stopped Standby with input clocks running	220 110 220	320 200	μΑ (max μΑ (max μΑ

AC Electrical Characteristics

The following specifications apply for AGND=DGND=0V, VA=VD=+5.0V_{DC}, f_{MCLK} =24MHz, t_{MCLK} =1/ f_{MCLK} , t_r =t_f=5ns, R_s=25 Ω . Boldface limits apply for T_A=T_J=T_{MIN} to T_{MAX}; all other limits T_A=T_J=25°C. (Notes 7 & 8)

Symbol	Parameter	Conditions	Typical (Note 9)	Limits (Note 10)	Units (Limits)
f _{MCLK}	Maximum MCLK Frequency			24	MHz (min)
	MCLK Duty Cycle			40 60	% (min) % (max)
t _{MCLK}	MCLK period		41		ns (min)
t _{SCNL}	SampCLK falling edge before NewLine falling edge			3	t _{MCLK} (min)
t _{SampCLK}	SampCLK period			4	t _{MCLK} (min)
t _{SampLo}	Low time for SampCLK		50		ns (min)
t _{SampHi}	High time for SampCLK		50		ns (min)
t _{SampSU}	SampCLK falling edge before rising edge of MCLK			4	ns (min)
t _{DDO}	falling edge of MCLK before new valid data			40	ns (max)
t _{HDO}	hold time of current data from falling edge of MCLK			15	ns (min)
t _{SCLK}	D2(SCLK) Serial Clock Period		1		t _{MCLK} (min)
t _{DSU}	Input data setup time before D2(SCLK) rising edge			0	ns (min)
t _{DH}	Input data hold time after D2(SCLK) rising edge			3	ns (min)
t _{SCLKLA}	D2(SCLK) rising edge after bit B0 before D1(Latch) rising edge			3	ns (min)
t _{LASCLK}	D1(Latch) rising edge before next D2(SCLK) rising edge			3	ns (min)
t _{LA}	High time for D1(Latch)			3	t _{MCLK} (min)
t _{LANL}	D1(Latch) rising edge before NewLine falling edge			3	t _{SampCLK} (min)

Note 1: Absolute Maximum Ratings indicate limits beyond which damage to the device may occur. Operating Ratings indicate conditions for which the device is functional, but do not guarantee specific performance limits. For guaranteed specifications and test conditions, see the Electrical Characteristics. The guaranteed specifications apply only for the test conditions listed. Some performance characteristics may degrade when the device is not operated under the listed test conditions.

Note 2: All voltages are measured with respect to GND=AGND=DGND=0V, unless otherwise specified.

Note 3: When the input voltage (V_{1N}) at any pin exceeds the power supplies $(V_{1N} < \text{GND or } V_{1N} > \text{VA or VD})$, the current at that pin should be limited to 25mA. The 50mA maximum package input current rating limits the number of pins that can simultaneously safely exceed the power supplies with an input current of 25mA to two.

Note 4: The maximum power dissipation must be derated at elevated temperatures and is dictated by T_Jmax , Θ_{JA} and the ambient temperature, T_A . The maximum allowable power dissipation at any temperature is $P_D = (T_Jmax - T_A) / \Theta_{JA}$. $T_Jmax = 150^{\circ}C$ for this device. The typical thermal resistance (Θ_{JA}) of this part when board mounted is 84°C/W for the M20B SOIC package.

Note 5: Human body model, 100pF capacitor discharged through a $1.5 k\Omega$ resistor.

Note 6: See AN450 "Surface Mounting Methods and Their Effect on Product Reliability" or the section titled "Surface Mount" found in any National Semiconductor Linear Data Book for other methods of soldering surface mount devices.





Note 8: To guarantee accuracy, it is required that VA and VD be connected together to the same power supply with separate bypass capacitors at each supply pin.

Note 9: Typicals are at $T_J=T_A=25^{\circ}C$, $f_{MCLK}=24MHz$, and represent most likely parametric norm.

Note 10: Tested limits are guaranteed to National's AOQL (Average Outgoing Quality Level).

Note 11: Integral non-linearity error is defined as the deviation of the analog value, expressed in LSBs, from the straight line that best fits the actual transfer function of the ADC.

Note 12: V_{REF} is defined as the CCD OS voltage for the reference period following the reset feedthrough pulse. V_{WHITE} is defined as the peak CCD pixel output voltage for a white (full scale) image with respect to the reference level, V_{REF} . V_{RFT} is defined as the peak positive deviation above V_{REF} of the reset feedthrough pulse. The maximum correctable range of pixel-to-pixel V_{WHITE} variation is defined as the maximum variation in V_{WHITE} (due to PRNU, light source intensity variation, optics, etc.) that the LM9810/20 can correct for using its internal PGA.



Note 13: PGA Gain Error is the maximum difference between the measured gain for any PGA code and the ideal gain calculated by using the formula $Gain_{PGA}\left(\frac{V}{V}\right) = G_0 + X \frac{PGA \text{ code}}{32}$ where $X = (G_{31} - G_0)\frac{32}{31}$.

Note 14: Full Channel INL and DNL are tested with CDS disabled, negative signal polarity, and a single OS input with a gain register setting of 1 (000001b) and an offset register setting of 0 (000000b).

Note 15: The digital supply current (ID) does not include the load, data and switching frequency dependent current required to drive the digital output bus on pins (D5 - D0). The current required to switch the digital data bus can be calculated from: Isw = 2*Nd*Psw*CL*VD/tSampCLK where Nd is total number of data pins, Psw is the probability of each data bit switching, CL is the capacitive loading on each data pin, VD is the digital supply voltage and tSampCLK is the period of the SampCLK signal. Since Nd is 6, Psw should be .5, and VD is nominally 5V, the switching current can usually be calculated from: Isw = 30*CL/tSampCLK. For example, if the capacitive load on each digital output pin (D5 - D0) is 20pF and the period of tSampCLK is 1/6MHz or 167ns , then the digital switching current would be 7.2mA. The calculated digital switching current will be drawn through the VD pin and should be considered as part of the total power budget for he LM9810/20.

Pin Descri	Analog Power
VA	This is the positive supply pin for the analog supply. It should be connected to a voltage source of $+5V$ and bypassed to AGND with a 0.1µF monolithic capacitor in parallel with a 10µF tantalum capacitor.
AGND	This is the ground return for the analog sup- ply.
	Analog I/O
OS _R , OS _G , OS _B ,	Analog Inputs. These inputs (for Red, Green, and Blue) should be tied to the sen- sor's OS (Output Signal) through DC block- ing capacitors.
RefBypass	Internally generated reference voltage bypass pin. It should be bypassed to AGND through a .05uF monolithic capacitor.
V _{REF+,} V _{REFMID,} V _{REF-}	Voltage reference bypass pins. They should each be bypassed to AGND through a .05uF monolithic capacitor.
	Input & Timing Control
MCLK	Master Clock. The ADC conversion rate will be a maximum of ¼ of MCLK. Nominally 24MHz.
SampCLK	Sample Clock. SampCLK controls the con- version rate of the ADC (up to ¼ of the MCLK rate) and sample timing. The signal level is sampled while SampCLK is low and held on the rising edge of SampCLK. When CDS is enabled, the falling edge of SampCLK causes the CCD reference level to be held. If CDS is not enabled, V _{REF+} or V _{REF} . is held on the falling edge of SampCLK, depending on the programmed signal polarity. SampCLK is also used with NewLine to clamp the exter- nal coupling capacitors.
NewLine	New Line signal. Used to indicate the start of active pixels on a new line, to allow clamping of the AC coupling caps, and to allow programming of the configuration register. When NewLine is high and SampCLK is low, the OS inputs will be connected to either V_{REF+} or V_{REF-} . On the first rising edge of MCLK after NewLine goes low, the internal mux and the offset and gain settings will be set to the appropriate values for the first color of the next line set in the color mode setting in the Sampler and Color Mode Register. When NewLine is low, D[5-0] transmit the pixel conversion data from the ADC. When NewLine is high, D[5-0] enter TRI-STATE and D2, D1 and D0 act as a serial interface for programming the configuration registers.

	0	Digital Pov	ver	
VD	supply source	. It should	be conne d bypass	pin for the digita ected to a voltage ed to DGND with a r.
DGND	This is ply.	the groun	d return f	or the digital sup
		Digital I/	0	
D5-D0	low, th the AD NewLin STATE face fo ters.	e 10 or 12 OC are mul e is high, t and D2, D r writing to	bit conve tiplexed to he output of & D0 ac o the conf	Then NewLine is ersion results of o D5-D0. When drivers enter TR t as a serial inter iguration regis-
LM9810 Output Mode (NewLine Low)	MCLK	0, MCLK1	, MCLK2,	MCLK3
D5	b9,	b9,	b3,	b3
D4	b8,	b8,	b2,	b2
D3	b7,	b7,	b1,	b1
D2	b6,	b6,	b0,	b0
D1	b5,	b5,	0,	0
D0	b4,	b4,	0,	0
LM9820 Output Mode (NewLine Low)	MCLK	0, MCLK1	, MCLK2,	MCLK3
D5	b11,	b11,	b5,	b5
D4	b10,	b10,	b4,	b4
D3	b9,	b9,	b3,	b3
D2	b8,	b8,	b2,	b2
D1	b7,	b7,	b1,	b1
D0	b6,	b6,	b0,	b0
Input Mode (NewLine High)				
D5-D3	Don't (Care		
D2 (SCLK)		Data Cloc		
D1 (Latch)	D1(Lat When shifted the ad avoid e registe	ch) is low, D1(Latch) into D0(S dressed co erroneous	data is sh goes high DI) will be onfiguratio writes to ch) should	nal. When ifted into D0(SDI) n, the last nine bit e used to progran on register. To the configuration d be pulled low
D0 (SDI)	rising e	edge. Thre	e addres	valid on D2(SCLK s bits followed by nould be shifted





Address (Decimal)		Address (Binary)				Data	a Bits		
	A2	A1	A0	B5	B4	B3	B3	B2	B1
_						Sampler and	d Color Mode		
0	0	0	0	CDS	Polarity	N/A	Mode2	Mode1	Mode
					-	Red DAC O	ffset Setting		
1	0	0	1	Polarity	MSB				LSE
						Green DAC	Offset Setting	•	
2	0	1	0	Polarity	MSB				LSE
						Blue DAC C	offset Setting		
3	0	1	1	Polarity	MSB				LSB
						Red Gai	n Setting		
4	1	0	0	x3	MSB				LSB
_						Green Ga	in Setting		
5	1	0	1	x3	MSB				LSE
					-	Blue Ga	in Setting		
6	1	1	0	x3	MSB				LSB
7					Pro	duction Test	and Power D	own	
7	1	1	1	Test	Test	Test	Test	Test	PD

Parameter (Address)			Cont	rol Bits	Result		
			San	pler and Color Mode (0)			
CDS Enable (0)	<u>B5</u> 0 1			CDS Enabl Single Ended (CDS			
Signal Polarity (0)	<u>B4</u> 0 1			Negative Pol Positive Pol	-		
	B2	B1	B0				
	0	0	0	2nd line: Mu	$ \begin{aligned} & x = OS_R, Gain & Offset = R \\ & x = OS_G Gain & Offset = G \\ & x = OS_B Gain & Offset = B \\ & repeat \end{aligned} $		
	0	0	1	pixel rate:	cts OS_B input. Gain & Offset change at the Offset = R, G, B, R, G, B		
	0	1	0	RESERVED			
Color Mode	0	1	1	Monochrome Mux selects OS _R	input. Gain & Offset = R		
(0)	1	0	0	Monochrome Mux selects OS _G	input. Gain & Offset = G		
	1	0	1	Monochrome Mux selects OS _B	input. Gain & Offset = B		
	1	1	0	*1st line: Ga	Gain & Offset change at the pixel rate: in & Offset = G,R,G,R, in & Offset = B,G,B,G, repeat rite to this register		
	1	1	1	rate: *1st line: Gain	B input. Gain & Offset change at the pixel & Offset = R,G,B,G,R,G,B, & Offset = B,G,R,G,B,G,R, repeat vrite to this register		

Γ

Parameter (Address)			Contr	ol Bits			R	esult
	I	Red, Gre	een and	Blue Of	fset DAC	Setting	s (1, 2 & 3)	
Offset Polarity (1,2 & 3)	<u>B5</u> 0 1					ositive Off egative Of		
Offset Value (1,2 & 3)	B4(MSB)	В3	B2	B1	B0(LSB)		Offset = 5LSBs * Off Offset = 20LSBs * Of	
	<u>B5</u>	<u>B4</u>	<u>B3</u>	<u>B2</u>	<u>B1</u>	<u>B0</u>	<u>Typical Offset (</u>	with PGA Gain = 1)
	(SIGN) 0	(MSB) 0	0			(LSB) 0	LM9810 LSBs 0.00	LM9820 LSBs 0.00
	0	0	0	0	0	1	+5	+20
	0	0	0	0	1	0	+10	+40
	•••	•••	•••	•••	•••	•••	•••	•••
Typical Offset	0	1	1	1	1	0	+150	+600
Values	0	1	1	1	1	1	+155	+620
(1,2 & 3)	1	0	0	0	0	0	0	0
	1	0	0	0	0	1	-5	-20
	1	0	0	0	1	0	-10	-40
	•••	•••	•••	•••	•••	•••	•••	•••
	1	1	1	1	1	0	-150	-600
	1	1	1	1	1	1	-155	-620
	1 1	Red,	Green a	and Blue	e Gain Se	ettings (4	4,5 & 6)	
Boost Gain Enable (4,5 & 6)	<u>B5</u> 0 1					ost Gain = ost Gain =		
PGA Gain Value (4,5 & 6)	B4	В3	B2	B1	В0	PGA Gai	in (V/V) =.933 + 0.066	37 * (PGA Gain Value
Gain (4,5 & 6)			<u></u>	Gai	n = Boost (Gain * PGA	Gain	
	<u>B5</u>	B4	<u>B3</u>	<u>B2</u>	<u>B1</u>	<u>B0</u>		cal Gain
	(x3) 0	(MSB) 0	0	0	0	(LSB) 0		V/V)).93
	0	0	0	0	0	1		1.00
	0	0	0	0	1	0		1.13
	•••	•••	•••	•••	•••	•••		•••
Turked Color	0	1	1	1	0	1	2	2.87
Typical Gain	0	1	1	1	1	0		2.93
Values	0	1	1	1	1	1		3.00
(4, 5 & 6)	•••	•••	•••	•••	•••	•••	•	•••
	1	0	0	0	0	0		2.79
	1	0	0	0	0	1	3	3.00
	1	0	0	0	1	0		3.20
	•••	•••	•••	•••	•••	•••		•••
	1	1	1	1	0	1		3.60
					1 4	0	1 9	3.80
	1 1	1 1	1 1	1	1	1		9.00

Parameter (Address)			Contro	ol Bits			Result
		F	Production	on Test a	and Pow	er Down	ı (7)
Production Test (7)	В5	В4	В3	B2	B1	Should	d all be set to zero for normal operation
Power Down Enable (7)	<u>B0</u> 0 1				No	rmal Opera Power Dov	ation vn

Applications Information

1.0 Programming the LM9810/20

1.1 Writing to the Configuration Register

When NewLine is high, D2, D1 & D0 act as a serial interface for writing to the configuration registers. D2 is the input serial clock (SCLK), D0 is the input data pin (SDI), and D1 is the latch and shift enable signal (Latch). When D1(Latch) is low, serial data is shifted into D0(SDI), and must be valid on each rising edge of D2(SCLK). Three register address bits followed by six data bits should be shifted into D0(SDI), MSB first. When D1(Latch) transitions from low to high, the last 6 data bits will be stored into the configuration register addressed by the previous 3 address bits (as shown in Diagram 3). D1(Latch) must remain high for at least 3 cycles of the serial clock on D2(SCLK) to write to the configurtion register.

1.2 CDS Mode

The LM9810/20 uses a high-performance CDS (Correlated Double Sampling) circuit to remove many sources of noise and error from the CCD signal. It also supports CIS image sensors with a single sampling mode.

Figure 1 shows the output stage of a typical CCD and the resulting output waveform:



Figure 1: CDS

Capacitor C1 converts the electrons coming from the CCD's shift register to an analog voltage. The source follower output stage (Q2) buffers this voltage before it leaves the CCD. Q1 resets the voltage across capacitor C1 between pixels at intervals 2 and 5. When Q1 is on, the output signal (OS) is at its most positive voltage. After Q1 turns off (period 3), the OS level represents the residual voltage across C1 (V_{RESIDUAL}). V_{RESIDUAL} includes charge injection from Q1, thermal noise from the ON resistance of Q1, and other sources of error. When the shift register clock (Ø1) makes a low to high transition (period 4), the electrons from the next pixel flow into C1. The charge across C1 now contains the voltage proportional to the number of electrons plus V_{RESIDUAL}, an error term. If OS is sampled at the end of period 3, and that voltage is subtracted from the OS at the end of period 4, the V_{RESIDUAL} term is canceled and the noise on the signal is

reduced ([V_{SIGNAL} + $V_{RESIDUAL}$]- $V_{RESIDUAL}$ = V_{SIGNAL}). This is the principal of Correlated Double Sampling.

If the LM9810/20 is programmed for correlated double sampling (bit B5 of register 0 is cleared), then the falling edge of SampCLK should occur toward the end of period 3 and the rising edge of SampCLK should occur towards the end of period 4. While SampCLK is high, the Reference level (V_{RESIDUAL}) is sampled, and it is held at the falling edge of SampCLK. While SampCLK is low, the signal level (V_{SIGNAL}+ V_{RESIDUAL}) is sampled and it is held at the rising edge of SampCLK. The output from the sampler is the potential difference between the two samples, or V_{SIGNAL}.

1.3 CIS Mode

The LM9810/20 supports CIS (Contact Image Sensor) devices by offering a sampling mode for capturing positive going signals, as opposed to the CCD's negative going signal. The output signal of a CIS sensor (Figure 2) differs from a CCD signal in two primary ways: its output increases with increasing signal strength, and it does not usually have a reference level as an integral part of the output waveform of every pixel.



When the LM9810/20 is in CIS mode (Register 0, B5=1), it uses either V_{REF+} or V_{REF}. depending on the signal polarity setting (B4 of the Sampling and Color Mode register) as the reference (or black) voltage for each pixel. If the signal polarity is set to one, then V_{REF}. will be held on the falling edge of SampCLK and the OS signal will be held on the rising edge of SampCLK. If it is set to zero, then V_{REF+} will be held on the falling edge of SampCLK. If it is set to ing edge of SampCLK should occur near the end of period 4, and at least 50ns after the falling edge of SampCLK.

1.4 Multiplexer/Channel Switching

The offset and gain settings automatically switch after each ADC conversion according to the color mode setting in the Sampler and Color Mode register (register 0). For example, if the color mode (bits B2,B1 & B0) is set to 001, the offset and gain will alternately switch between the R, G and B settings after each conversion. The input multiplexer never changes during a line, but if the color mode is set to Line Rate Color (000), the mux will automatically switch after each new line.

The offset and gain settings will always start with the first channel of the programmed mode after a falling edge on $\mathsf{NewLine}.$ For

example, the R offset and gain settings will be used for the first conversion following a falling edge on NewLine if the color mode is set to Single Input Color (001).

For the Single Input Color, Bayer and Green Stripe modes, the mux will always connect the OS_B input to the sampler. The offset and gain settings will alternate values every pixel according to the order indicated by the Sampler and Color Mode register (see Table 2). The first falling edge of NewLine following a write to the Sampler and Color Mode register will ready the offset and gain to cycle through the colors of the first line of the programmed color mode. Each subsequent falling edge of NewLine will switch the offset and gain settings to the first color of the next line. The LM9810/20's unused OS inputs should not be left unconnected. All three OS inputs should be tied together on the LM9810/20 side of the clamp capacitor (see Figure 3).



Figure 3: OS Connections for single output sensors

For the Line Rate Color mode, the mux will cycle through the OS_R , OS_G and OS_B inputs after each falling edge of NewLine. The R, G and B offset & gain settings will be used when the mux is set to the OS_R , OS_G and OS_B input, respectively. OS_R and the R offset & gain settings will always be used on the first line following a write register 0.

1.5 Data Latency

The latency through the LM9810/20 is 8 SampCLK periods plus one MCLK period. The data output on D5 - D0 (MSBs b11 - b6 or b9 - b4) represents data whose reference signal was sampled 8 tSampCLK + tMCLK + tSampSU earlier (see Diagram 1).

1.6 Programmable Gain

The output of the Sampler drives the input of the x3 Boost gain stage. The gain of the x3 Boost gain is 3V/V if bit B5 of the current color's gain register (registers 4,5, and 6) is set, or 1V/V if bit B5 is cleared. The output of the x3 gain stage is the input to the offset DAC and the output of the offset DAC is the input to the PGA (Programmable Gain Amplifier). The PGA provides 5 bits of gain correction over a 0.93V/V to 3V/V (-0.6 to 9.5dB) range. The x3 Boost gain stage and the PGA can be combined for an overall gain range of .93V/V to 9.0V/V (-6 to 19dB). The gain setting for each color (registers 4, 5 and 6) should be set during calibration to bring the maximum amplitude of the strongest pixel to a level just below the desired maximum output from the ADC. The PGA gain is determined by the following equation:

PGA Gain
$$\left(\frac{V}{V}\right)$$
 = 0.933 + .0667 (value in bits B4-B0)
Equation 1: PGA Gain

.

If the x3 Boost gain is enabled then the overall signal gain will be three times the PGA gain.

1.7 Offset DAC

The Offset DAC removes the DC offsets generated by the sensor and the LM9810/20's analog signal chain (see section 1.7.1, Internal Offsets). The DAC value for each color (registers 1,2 and 3) should be set during calibration to the lowest value that still results in an ADC output code greater than zero for all the pixels when scanning a black line. With a PGA gain of 1V/V, each LSB of the offset DAC typically adds the equivalent of 5 LM9810 LSBs or 20 LM9820 LSBs, providing a total offset adjustment range of \pm 150 LM9810 LSBs or \pm 590 LM9820 LSBs. The Offset DAC's output voltage is given by:

> $V_{DAC} = 9.75 \text{ mV} \cdot (\text{value in B4 - B0})$ Equation 2: Offset DAC Output Voltage

In terms of output codes, the offset is given by:

Offset = 5LSBs · (value in B4 - B0) · PGA Gain Equation 3: LM9810 Offset Equation

Offset = 20LSBs · (value in B4 - B0) · PGA Gain Equation 4: LM9820 Offset Equation

The offset is positive if bit B5 is cleared and negative if B5 is set. Since the analog offset is added before the PGA gain, the value of the PGA gain must be considered when selecting the offset DAC values.

1.7.1 Internal Offsets

Figure 4 is a model of the LM9810/20's internal offsets. Equation 5 shows how to calculate the expected output code given the input voltage (VIN), the LM9810/20 internal offsets (VOS1, VOS2, VOS3), the programmed offset DAC voltage (VDAC), the programmed gains (GB, GPGA) and the analog channel gain constant C.

C is a constant that combines the gain error through the AFE, reference voltage variance, and analog voltage to digital code conversion into one constant. Ideally, C = 2048 codes/V (4096 codes/2V) for the LM9820 and 512 codes/V (1024 codes/2V) for the LM9810. Manufacturing tolerances widen the range of C (see Electrical Specifications).



$$\begin{split} D_{OUT} &= (((V_{IN} + V_{OS1})G_B + V_{DAC} + V_{OS2})G_{PGA} + V_{OS1})C \\ \textbf{Equation 5: Output code calculation with internal offsets} \end{split}$$

Equation 6 is a simplification of the output code calculation, neglecting the LM9810/20's internal offsets.

 $D_{OUT} = (V_{IN}G_B + V_{DAC})G_{PGA}C$

Equation 6: Simplified output code calculation

1.8 Power Down Mode

Setting the Power Down (bit B0 of register 7) puts the device in a low power standby mode. The analog sections are turned off to conserve power. The digital logic will continue to operate if MCLK continues, so for minimum power dissipation MCLK should be stopped when the LM9810/20 enters the Power Down mode. Recovery from Power Down typically takes 50µs (the time required for the reference voltages to settle to 0.5 LSB accuracy).

2.0 Clamping

To perform a DC restore across the AC coupling capacitors at the beginning of every line, the LM9810/20 implements a clamping function. When NewLine is high and SampCLK is low, all three OS inputs will be connected to either V_{REF+} or V_{REF-} , depending on B4 of the Sampling and Color Mode register. If B4 is set to one (positive signal polarity), then the OS inputs will be connected to V_{REF-} . If B4 is set to zero (negative signal polarity), then they will be connected to V_{REF+} .

2.1 Clamp Capacitor Selection

This section explains how to select appropriate clamp capacitor values.



Figure 5: OS Clamp Capacitor and Internal Clamp

The output signal of many sensors rides on a DC offset (greater than 5V for many CCDs) which is incompatible with the LM9810/20's 5V operation. To eliminate this offset without resorting to additional higher voltage components, the output of the sensor is AC coupled to the LM9810/20 through a DC blocking capacitor, $\mathsf{C}_{\mathsf{CLAMP}}$ The sensor's DOS output, if available, is not used. The value of this capacitor is determined by the leakage current of the LM9810/20's OS input and the output impedance of the sensor. The leakage through the OS input determines how quickly the capacitor value will drift from the clamp value of V_{REF+} or V_{REF-}, which then determines how many pixels can be processed before the droop causes errors in the conversion (±0.1V is the recommended limit for CDS operation). The output impedance of the sensor determines how quickly the capacitor can be charged to the clamp value during the black reference period at the beginning of every line.

The minimum clamp capacitor value is determined by the maximum droop the LM9810/20 can tolerate while converting one sensor line. The minimum clamp capacitor value is much smaller for CDS mode applications than it is for CIS mode applications. The LM9810/20 input leakage current is considerably less when the LM9810/20 is operating in CDS mode. In CDS mode, the LM9810/20 leakage current should be no more than 20nA. With CDS disabled, which will likely be the case when CIS sensors are used, the LM9810/20 leakage current can be as high as 25uA at the maximum conversion rate.

2.1.1 CDS mode Minimum Clamp Capacitor Calculation:

The following equation takes the maximum leakage current into the OS input, the maximum allowable droop, the number of pixels on the sensor, and the pixel conversion rate, $f_{\mbox{SampCLK}}$, and provides the minimum clamp capacitor value:

$$C_{CLAMP MIN} = \frac{i}{dV} dt$$

$$= \frac{leakage current (A) number of pixels}{max droop(V)} \frac{f_{SampCLK}}{f_{SampCLK}}$$
Equation 7: CDS mode C_{CLAMP MIN} Calculation

For example, if the OS input leakage current is 20nA worst-case, the sensor has 2700 active pixels, the conversion rate is 2MHz ($t_{SampCLK} = 500ns$), and the max droop desired is 0.1V, the minimum clamp capacitor value is:

$$C_{CLAMP MIN} = \frac{20nA}{0.1V} \frac{2700}{2MHz}$$

= 270pF
Equation 8: CDS mode C_{CLAMP MIN} Example

2.1.2 CIS mode Minimum Clamp Capacitor Calculation:

If CDS is disabled, then the maximum LM9810/20 OS input leakage current can be calculated from:

$I_{leakage} = V_{SAT}f_{SampCLK}C_{SAMP}$

Equation 9: CIS mode Input Leakage Current Calculation

where VSAT is the peak pixel signal swing of the CIS OS output and CSAMP is the capacitance of the LM9810/20's internal sampling capacitor (2pF). Inserting this into Equation 7 results in:

$$C_{\text{CLAMP MIN}} = \frac{i}{dV} dt$$

$$= \frac{V_{\text{SAT}}}{t_{\text{SampCLK}}} C_{\text{SAMP} \max \text{droop(V)}} \text{num pixels}$$

Equation 10: CIS mode C_{CLAMP MIN} Calculation

with CSAMP equal to 2pF and VSAT equal to 2V (the LM9810/20's maximum input signal), then Equation 10 reduces to:

CLAMP MIN =
$$\frac{4p(F)(V)}{\max droop(V)}$$
 num pixels

In CIS mode (CDS disabled), the max droop limit must be much more carefully chosen, since any change in the clamp capacitor's DC value will affect the LM9810/20's conversion results. If a droop of one 10 bit LSB across a line is considered acceptable, then the allowed droop voltage is calculated as: 2V/1024, or

С

approximately 2mV. If there are 2700 active pixels on a line then:

$$C_{\text{CLAMP MIN}} = \frac{4p(F)(V)}{2mV} 2700$$
$$= 5.4 \text{uF}$$

Equation 12: CIS mode C_{CLAMP MIN} Calculation Example

2.1.3 Maximum Clamp Capacitor Calculation:

The maximum size of the clamp capacitor is determined by the amount of time available to charge it to the desired value during the optical black portion of the sensor output. The internal clamp is on when NewLine is high and SampCLK is low. If the applied SampCLK is low for half its cycle, then the available charge time per line can be calculated using:

$$t_{CLAMP} = \frac{Number of optical black pixels}{2f_{SampCLK}}$$

Equation 13: Clamp Time Per Line Calculation

For example, if a sensor has 18 black reference pixels and fSamp-CLK is 2MHz with a 50% duty cycle, then tCLAMP is 4.5μ s.

The following equation takes the number of optical black pixels, the amount of time (per pixel) that the clamp is closed, the sensor's output impedance, and the desired accuracy of the final clamp voltage and provides the maximum clamp capacitor value that allows the clamp capacitor to settle to the desired accuracy within a single line:

$$C_{\text{CLAMP MAX}} = \frac{t}{R} \frac{1}{\ln(\text{accuracy})}$$
$$= \frac{t_{\text{CLAMP}}}{R_{\text{CLAMP}}} \frac{1}{\ln(\text{accuracy})}$$

Equation 14: CCLAMP MAX for a single line of charge time

Where t_{CLAMP} is the amount of time (per line) that the clamp is on, R_{CLAMP} is the output impedance of the CCD plus 50 Ω for the LM9810/20's internal clamp switch, and accuracy is the ratio of the worst-case initial capacitor voltage to the desired final capacitor voltage. If tCLAMP is 4.5 μ s, the output impedance of the sensor is 1500 Ω , the worst case voltage change required across the capacitor (before the first line) is 5V, and the desired accuracy after clamping is to within 0.1V (accuracy = 5/0.1 = 50), then:

$$C_{\text{CLAMP MAX}} = \frac{4.5 \mu s}{1550 \Omega \ln(50)}$$

= 728 pF

Equation 15: C_{CLAMP MAX} Example

The final value for C_{CLAMP} should be less than or equal to $C_{CLAMP\;MAX},$ but no less than $C_{CLAMP\;MIN}.$

In some cases, depending primarily on the choice of sensor, $C_{\rm CLAMP\ MAX}$ may actually be less than $C_{\rm CLAMP\ MIN}$, meaning that the capacitor can not be charged to its final voltage during the black pixels at the beginning of a line and hold it's voltage without drooping for the duration of that line. This is usually not a problem because in most applications the sensor is clocked continuously as soon as power is applied. In this case, a larger capacitor can be used (guaranteeing that the $C_{\rm CLAMP\ MIN}$ requirement is met), and the final clamp voltage is forced across the capacitor over multiple lines. This equation calculates how many lines are

required before the capacitor settles to the desired accuracy:

lines =
$$\left(R_{CLAMP} \frac{C_{CLAMP}}{t_{CLAMP}} \right) ln\left(\frac{lnitial Error Voltage}{Final Error Voltage} \right)$$

Equation 16: Number of Lines Required for Clamping

Using the values shown before and a clamp capacitor value of 0.01μ F, this works out to be:

lines =
$$\left(1550\frac{0.01\mu F}{4.5\mu s}\right)\ln\left(\frac{5V}{0.1V}\right)$$
 = 13.5 lines
Equation 17: Clamping Lines Required Example

In this example, a 0.01µF capacitor takes 14 lines after power-up to charge to its final value. On subsequent lines, the only error will be the droop across a single line which should be significantly less than the initial error. If the LM9810/20 is operating in CDS mode and multiple lines are used to charge up the clamping capacitors after power-up, then a clamp capacitor value of 0.01µF should be significantly greater than the calculated C_{CLAMP MIN} value and can virtually always be used.

If the LM9810/20 is operating in CIS mode, then significantly larger clamp capacitors must be used. Fortunately, the output impedance of most CIS sensors is significantly smaller than the output impedance of CCD sensors, and RCLAMP will be dominated by the 50 Ω from the LM9810/20's internal clamp switch. With a smaller RCLAMP value, the clamp capacitors will charge faster.

3.0 Performance Considerations

3.1 Power Supply

The LM9810/20 should be powered by a single +5V source. The analog supplies (VA) and the digital supply (VD) are brought out individually to allow separate bypassing for each supply input. They should *not* be powered by two or more different supplies.

In systems with separate analog and digital +5V supplies, all the supply pins of the LM9810/20 should be powered by the analog +5V supply. Each supply input should be bypassed to its respective ground with a 0.1 μ F capacitor located as close as possible to the supply input pin. A single 10 μ F tantalum capacitor should be placed near the VA supply pin to provide low frequency bypassing.

To minimize noise, keep the LM9810/20 and all analog components as far as possible from noise generators, such as switching power supplies and high frequency digital busses. If possible, isolate all the analog components and signals (OS, reference inputs and outputs, VA, AGND) on an analog ground plane, separate from the digital ground plane. The two ground planes should be tied together at a single point, preferably the point where the power supply enters the PCB.

3.2 SampCLK Timing

SampCLK is used to time the stages of the LM9810/20's sampler, offset DAC and programmable gain amplifier. To allow for optimum input signal sampling times, SampCLK may be applied asynchronously to MCLK. The LM9810/20's ADC is synchronized with the its AFE (including the sampler, the offset DAC and the PGA) by MCLK.

The LM9810/20's internal ADC clock is created through a combi-

nation of the applied SampCLK and MCLK signals. MCLK is used to synchronize the applied SampCLK signal. The internal ADC clock will go low after the falling edge of SampCLK is clocked by a rising of MCLK. The ADC clock will stay low for two MCLK cycles and then go high. It will stay high until the next falling edge of SampCLK is clocked by MCLK. Figure 6 illustrates this SampCLK, MCLK, and ADC clock timing relationship.



The LM9810/20 is a densely designed, mixed-signal, monolithic semiconductor. In creating the timing for the LM9810/20, it must be considered that internal events, such as ADC sampling, and output data bus switching can potentially affect coincident events such as input signal sampling or offset DAC settling. One event can interfere with another by coupling noise on shared resources such as the supply lines, internal voltage references, or the silicon substrate.

To optimize the performance of the LM9810/20, SampCLK should be timed so that the input signal hold times do not coincide with output data switching and ADC clock transitions. In other words, the rising and falling edges of SampCLK should not be placed close to ADC clock edges or to output data transitions. SampCLK edges should be at least 20ns away from ADC clock edges to avoid interference between the ADC and the sampler. SampCLK edges should also be placed at least 40ns after output data transition times to avoid transition noise coupling.

Figure 6 is an example of SampCLK timing that will meet these requirements at the maximum MCLK frequency of 24MHz. In diagram 6, SampCLK transitions occur on MCLK falling edges which will keep them more than 20ns away from ADC transitions, and 40ns after output data transitions.



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